

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/771,992	SIEGRIST ET AL.	
Examiner	Art Unit	_
John L. Shew	2664	

SEARCHED			
Class	Subclass	Date	Examiner
370	230	7/26/2005	JS
	351-356		
	389,401		
	410,465		
	466		
379	88.01	7/26/2005	JS
	121.04		
	207.02		
	219		
	221.06		
	221.15		
	227		
	265.03		
	265.09		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	<u></u>		

(INCLUDING SEARCH STRATEGY)  DATE EXMR			
		——————————————————————————————————————	EXIVIR
`\			
· · · · · · · · · · · · · · · · · · ·			
• .	,		
	'		
		· · · · · · · · · · · · · · · · · · ·	

Search Notes (continued)



Application/Control	No
09/771,992	
Evaminer	

John L. Shew

Applicant(s)/Pa	atent under
SIEGRIST ET	AL.
Art Unit	
2664	

	SEAR	CHED	
Class	Subclass	Date	Examiner
379	265.11	7/26/2005	JS

379	265.11	7/26/2005	JS
	388.07		
	390.01		
	420.03		
381	56,57	7/26/2005	JS
	58,60		
	82,83		
	92,93		,
	94.5		
	94.8		
	. 94.9		
	95		
		-	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	I		
	.		

(INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
,		
•		
·		
,		